

				ATTY. DOCKET NO.:		APPLICATION NO.:	
				81421-4038			
				APPLICANT:			
				Steen Ørsted ANDERSEN			
				FILING DATE:		GROUP:	
				March 9, 2004			

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SDI	AA	6,240,933 B1	6/2001	Bergman	134	1.3	X
	AB	6,312,797	11/2001	Yokokawa et al.	428	336	
	AC	2002/0062841	5/2002	Twu et al.	134	3	
	AD						

FOREIGN PATENT DOCUMENTS								
		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
	AE							
	AF							
	AG							
	AH							
	AI							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)		
SDI	AJ	Seiji Fujino et al., "Silicon Wafer Direct Bonding through the Amorphous Layer", Jp.n.. J. Appl. Phys., Vol. 34, pp. 1322-1324 (1995)
	AK	
	AL	
	AM	
	AN	
	AO	

<p style="text-align: center;">EXAMINER</p> <p style="text-align: center;"><i>Steen Ørsted Andersen</i></p>	<p style="text-align: center;">DATE CONSIDERED</p> <p style="text-align: center;">6/7/05</p>
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



ATTY. DOCKET NO.: 4717-10500		APPLICATION NO.: 10/808,288
APPLICANT: C. Maleville et al.		
FILING DATE: March 25, 2004		GROUP: 2812

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
SDI	AA	2002/0020436 A1	2/2002	Bergman	134	30	
	AB						
	AC						
	AD						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
							YES	NO
SDI	AE	EP 0971 396 A1	1/2000	Europe			X	
	AF							
	AG							
	AH							
	AI							

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

	AJ)
	AK	
	AL	
	AM	
	AN	
	AO	

EXAMINER <i>Stanette Dore</i>	DATE CONSIDERED 6/7/05
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*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.